

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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	K	US-			
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**NON-PATENT DOCUMENTS**

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	U	PCT-Easy, User Reference Manual, January 1999, <a href="http://pcteasy.wipo.int/en/index.html">http://pcteasy.wipo.int/en/index.html</a> ).
	V	<a href="http://www.inventnet.com">www.inventnet.com</a> , 11/7/1996, Screen Print
	W	<a href="http://www.lloydwise.com">www.lloydwise.com</a>
	X	Dutton, Gail, "Protecting Intellectual property." Chemical Market Reporter, March 23, 1998.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.